

IDS 04/27/2006

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>				Docket Number (Optional) <b>DE920020016US1</b>		Application Number <b>10/620957</b>			
				Applicant(s) <b>Appinger et al</b>				<b>RECEIVED</b> <b>CENTRAL FAX CENTER</b> <b>APR 27 2006</b>	
				Filing Date <b>7/30/2003</b>		Group Art Unit <b>2138</b>			
<b>U.S. PATENT DOCUMENTS</b>									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
<b>FOREIGN PATENT DOCUMENTS</b>									
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO		
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>									
PC		"LFSR-Coded Test Patterns for Scan Designs" by B. Kouemmann, Pages 237-242							
PC		"Decompression of Test Data Using Variable-Length Seed LFSRs" by J. Rajski et al, 1995 IEEE, Pages 426-433							
EXAMINER  /Phung Chung/				DATE CONSIDERED  06/09/2006					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									